

APPENDIX B: ADT SAR MEASUREMENT SYSTEM



APPENDIX C: PHOTOGRAPHS OF SYSTEM VALIDATION





APPENDIX D: SYSTEM CERTIFICATE & CALIBRATION

D1: PHANTOM



APPENDIX D: SYSTEM CERTIFICATE & CALIBRATION

D1: SAM PHANTOM

Schmid & Partner Engineering AG

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Certificate of conformity / First Article Inspection

Item	SAM Twin Phantom V4.0
Type No	QD 000 P40 CA
Series No	TP-1150 and higher
Manufacturer / Origin	Untersee Composites Hauptstr. 69 CH-8559 Fruthwilen Switzerland

Tests

The series production process used allows the limitation to test of first articles. Complete tests were made on the pre-series Type No. QD 000 P40 AA, Serial No. TP-1001 and on the series first article Type No. QD 000 P40 BA, Serial No. TP-1006. Certain parameters have been retested using further series units (called samples).

Test	Requirement	Details	Units tested
Shape	Compliance with the geometry according to the CAD model.	IT'IS CAD File (*)	First article, Samples
Material thickness	Compliant with the requirements according to the standards	2mm +/- 0.2mm in specific areas	First article, Samples
Material parameters	Dielectric parameters for required frequencies	200 MHz - 3 GHz Relative permittivity < 5 Loss tangent < 0.05.	Material sample TP 104-5
Material resistivity	The material has been tested to be compatible with the liquids defined in the standards	Liquid type HSL 1800 and others according to the standard.	Pre-series, First article

Standards

- [1] CENELEC EN 50361
- [2] IEEE P1528-200x draft 6.5
- [3] IEC PT 62209 draft 0.9

(*) The IT'IS CAD file is derived from [2] and is also within the tolerance requirements of the shapes of [1] and [3].

Conformity

Based on the sample tests above, we certify that this item is in compliance with the uncertainty requirements of SAR measurements specified in standard [1] and draft standards [2] and [3].

Date

28.02.2002

Signature / Stamp

F. Bumbult

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Volker Kapp

D2: DOSIMETRIC E-FIELD PROBE



Accredited by the Swiss Accreditation Service (SAS)

Accreditation No.: **SCS 108**

The Swiss Accreditation Service is one of the signatories to the EA
 Multilateral Agreement for the recognition of calibration certificates

Client **ADT (Auden)**

Certificate No: **EX3-3504_Jan09**

CALIBRATION CERTIFICATE

Object **EX3DV3 - SN:3504**

Calibration procedure(s) **QA CAL-01.v6, QA CAL-14.v3 and QA CAL-23.v3
 Calibration procedure for dosimetric E-field probes**

Calibration date: **January 21, 2009**

Condition of the calibrated item **In Tolerance**

This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI).
 The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.

All calibrations have been conducted in the closed laboratory facility: environment temperature (22 ± 3)°C and humidity < 70%.

Calibration Equipment used (M&TE critical for calibration)

Primary Standards	ID #	Cal Date (Certificate No.)	Scheduled Calibration
Power meter E4419B	GB41293874	1-Apr-08 (No. 217-00788)	Apr-09
Power sensor E4412A	MY41495277	1-Apr-08 (No. 217-00788)	Apr-09
Power sensor E4412A	MY41498087	1-Apr-08 (No. 217-00788)	Apr-09
Reference 3 dB Attenuator	SN: S5054 (3c)	1-Jul-08 (No. 217-00865)	Jul-09
Reference 20 dB Attenuator	SN: S5086 (20b)	31-Mar-08 (No. 217-00787)	Apr-09
Reference 30 dB Attenuator	SN: S5129 (30b)	1-Jul-08 (No. 217-00866)	Jul-09
Reference Probe ES3DV2	SN: 3013	2-Jan-09 (No. ES3-3013_Jan09)	Jan-10
DAE4	SN: 660	9-Sep-08 (No. DAE4-660_Sep08)	Sep-09
Secondary Standards	ID #	Check Date (in house)	Scheduled Check
RF generator HP 8648C	US3642U01700	4-Aug-99 (in house check Oct-07)	In house check: Oct-09
Network Analyzer HP 8753E	US37390585	18-Oct-01 (in house check Oct-08)	In house check: Oct-09

	Name	Function	Signature
Calibrated by:	Katja Pokovic	Technical Manager	
Approved by:	Niels Kuster	Quality Manager	

Issued: January 21, 2009

This calibration certificate shall not be reproduced except in full without written approval of the laboratory.



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Glossary:

TSL	tissue simulating liquid
NORM _{x,y,z}	sensitivity in free space
ConvF	sensitivity in TSL / NORM _{x,y,z}
DCP	diode compression point
Polarization ϕ	ϕ rotation around probe axis
Polarization ϑ	ϑ rotation around an axis that is in the plane normal to probe axis (at measurement center), i.e., $\vartheta = 0$ is normal to probe axis

Calibration is Performed According to the Following Standards:

- IEEE Std 1528-2003, "IEEE Recommended Practice for Determining the Peak Spatial-Averaged Specific Absorption Rate (SAR) in the Human Head from Wireless Communications Devices: Measurement Techniques", December 2003
- IEC 62209-1, "Procedure to measure the Specific Absorption Rate (SAR) for hand-held devices used in close proximity to the ear (frequency range of 300 MHz to 3 GHz)", February 2005

Methods Applied and Interpretation of Parameters:

- NORM_{x,y,z}**: Assessed for E-field polarization $\vartheta = 0$ ($f \leq 900$ MHz in TEM-cell; $f > 1800$ MHz: R22 waveguide). NORM_{x,y,z} are only intermediate values, i.e., the uncertainties of NORM_{x,y,z} does not effect the E²-field uncertainty inside TSL (see below *ConvF*).
- NORM(*f*)_{x,y,z}** = NORM_{x,y,z} * *frequency_response* (see Frequency Response Chart). This linearization is implemented in DASY4 software versions later than 4.2. The uncertainty of the frequency response is included in the stated uncertainty of *ConvF*.
- DCP_{x,y,z}**: DCP are numerical linearization parameters assessed based on the data of power sweep (no uncertainty required). DCP does not depend on frequency nor media.
- ConvF and Boundary Effect Parameters**: Assessed in flat phantom using E-field (or Temperature Transfer Standard for $f \leq 800$ MHz) and inside waveguide using analytical field distributions based on power measurements for $f > 800$ MHz. The same setups are used for assessment of the parameters applied for boundary compensation (alpha, depth) of which typical uncertainty values are given. These parameters are used in DASY4 software to improve probe accuracy close to the boundary. The sensitivity in TSL corresponds to NORM_{x,y,z} * *ConvF* whereby the uncertainty corresponds to that given for *ConvF*. A frequency dependent *ConvF* is used in DASY version 4.4 and higher which allows extending the validity from ± 50 MHz to ± 100 MHz.
- Spherical isotropy (3D deviation from isotropy)**: in a field of low gradients realized using a flat phantom exposed by a patch antenna.
- Sensor Offset**: The sensor offset corresponds to the offset of virtual measurement center from the probe tip (on probe axis). No tolerance required.

Probe EX3DV3

SN:3504

Manufactured:	December 15, 2003
Last calibrated:	August 30, 2007
Recalibrated:	January 21, 2009

Calibrated for DASY Systems

(Note: non-compatible with DASY2 system!)

DASY - Parameters of Probe: EX3DV3 SN:3504

Sensitivity in Free Space^A

Diode Compression^B

NormX	0.60 ± 10.1%	$\mu\text{V}/(\text{V}/\text{m})^2$	DCP X	94 mV
NormY	0.62 ± 10.1%	$\mu\text{V}/(\text{V}/\text{m})^2$	DCP Y	94 mV
NormZ	0.65 ± 10.1%	$\mu\text{V}/(\text{V}/\text{m})^2$	DCP Z	95 mV

Sensitivity in Tissue Simulating Liquid (Conversion Factors)

Please see Page 8.

Boundary Effect

TSL **900 MHz** **Typical SAR gradient: 5 % per mm**

Sensor Center to Phantom Surface Distance		2.0 mm	3.0 mm
SAR _{be} [%]	Without Correction Algorithm	10.0	6.0
SAR _{be} [%]	With Correction Algorithm	0.7	0.3

TSL **1750 MHz** **Typical SAR gradient: 10 % per mm**

Sensor Center to Phantom Surface Distance		2.0 mm	3.0 mm
SAR _{be} [%]	Without Correction Algorithm	8.0	4.9
SAR _{be} [%]	With Correction Algorithm	0.8	0.6

Sensor Offset

Probe Tip to Sensor Center **1.0 mm**

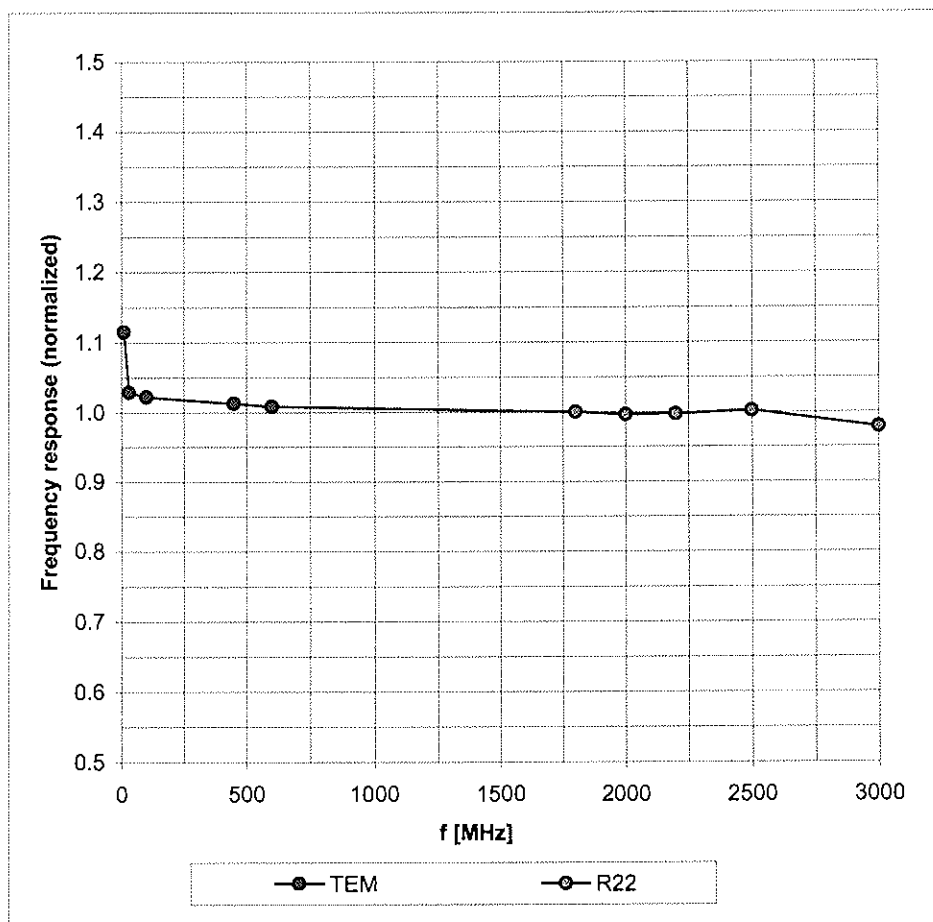
The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

^A The uncertainties of NormX,Y,Z do not affect the E²-field uncertainty inside TSL (see Page 8).

^B Numerical linearization parameter: uncertainty not required.

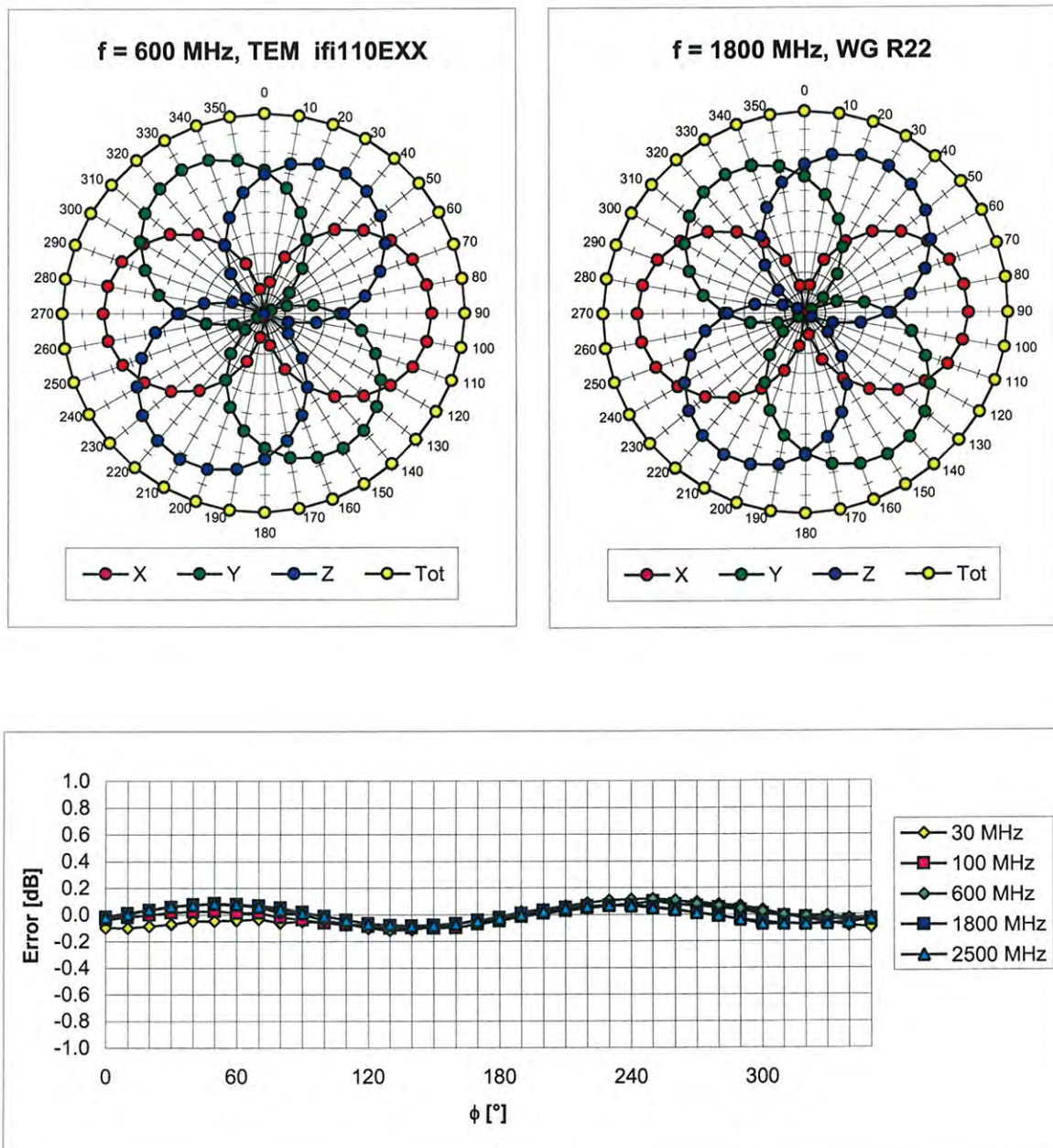
Frequency Response of E-Field

(TEM-Cell:ifi110 EXX, Waveguide: R22)



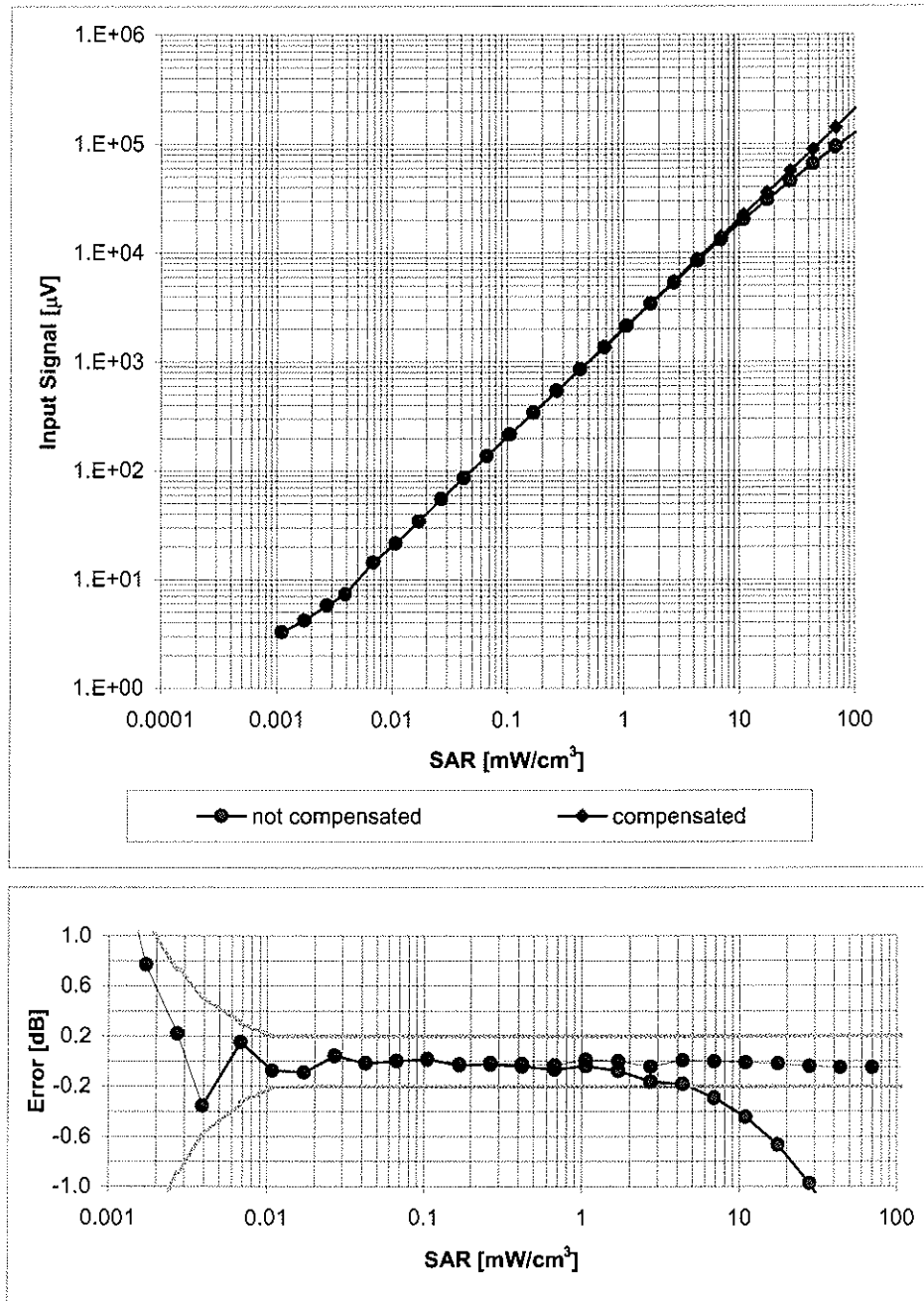
Uncertainty of Frequency Response of E-field: $\pm 6.3\%$ ($k=2$)

Receiving Pattern (ϕ), $\vartheta = 0^\circ$



Uncertainty of Axial Isotropy Assessment: $\pm 0.5\%$ ($k=2$)

Dynamic Range $f(\text{SAR}_{\text{head}})$ (Waveguide R22, $f = 1800 \text{ MHz}$)



Uncertainty of Linearity Assessment: $\pm 0.6\%$ ($k=2$)

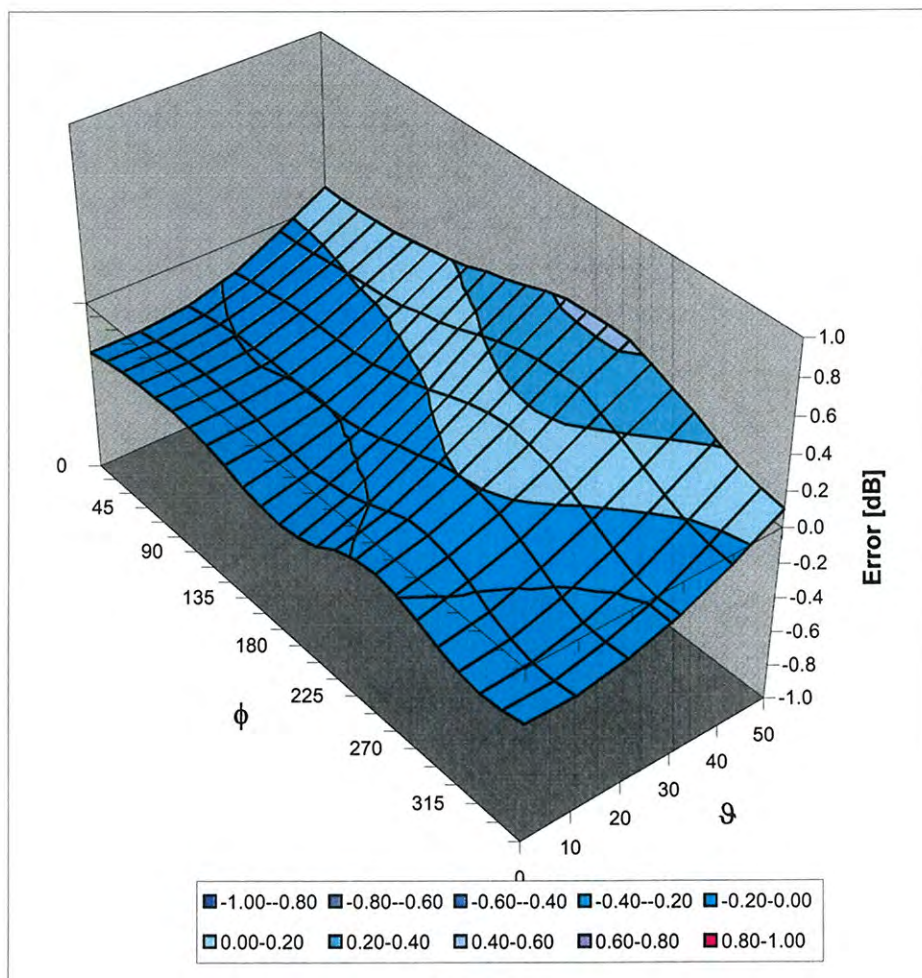
Conversion Factor Assessment

f [MHz]	Validity [MHz] ^c	TSL	Permittivity	Conductivity	Alpha	Depth	ConvF Uncertainty
900	± 50 / ± 100	Head	41.5 ± 5%	0.97 ± 5%	0.74	0.65	9.57 ± 11.0% (k=2)
1750	± 50 / ± 100	Head	40.1 ± 5%	1.37 ± 5%	0.56	0.64	8.53 ± 11.0% (k=2)
1950	± 50 / ± 100	Head	40.0 ± 5%	1.40 ± 5%	0.76	0.57	8.08 ± 11.0% (k=2)
2450	± 50 / ± 100	Head	39.2 ± 5%	1.80 ± 5%	0.53	0.66	7.67 ± 11.0% (k=2)
2600	± 50 / ± 100	Head	39.0 ± 5%	1.96 ± 5%	0.24	0.98	7.56 ± 11.0% (k=2)
5200	± 50 / ± 100	Head	36.0 ± 5%	4.66 ± 5%	0.42	1.70	4.65 ± 13.1% (k=2)
5300	± 50 / ± 100	Head	35.9 ± 5%	4.76 ± 5%	0.42	1.70	4.49 ± 13.1% (k=2)
5500	± 50 / ± 100	Head	35.6 ± 5%	4.96 ± 5%	0.42	1.70	4.39 ± 13.1% (k=2)
5600	± 50 / ± 100	Head	35.5 ± 5%	5.07 ± 5%	0.42	1.70	4.29 ± 13.1% (k=2)
5800	± 50 / ± 100	Head	35.3 ± 5%	5.27 ± 5%	0.42	1.70	4.40 ± 13.1% (k=2)
900	± 50 / ± 100	Body	55.0 ± 5%	1.05 ± 5%	0.50	0.73	9.71 ± 11.0% (k=2)
1750	± 50 / ± 100	Body	53.4 ± 5%	1.49 ± 5%	0.46	0.73	8.36 ± 11.0% (k=2)
1950	± 50 / ± 100	Body	53.3 ± 5%	1.52 ± 5%	0.43	0.73	8.21 ± 11.0% (k=2)
2450	± 50 / ± 100	Body	52.7 ± 5%	1.95 ± 5%	0.27	1.07	7.53 ± 11.0% (k=2)
2600	± 50 / ± 100	Body	52.5 ± 5%	2.16 ± 5%	0.25	1.10	7.33 ± 11.0% (k=2)
5200	± 50 / ± 100	Body	49.0 ± 5%	5.30 ± 5%	0.45	1.75	4.38 ± 13.1% (k=2)
5300	± 50 / ± 100	Body	48.9 ± 5%	5.42 ± 5%	0.45	1.75	4.06 ± 13.1% (k=2)
5500	± 50 / ± 100	Body	48.6 ± 5%	5.65 ± 5%	0.42	1.75	3.98 ± 13.1% (k=2)
5600	± 50 / ± 100	Body	48.5 ± 5%	5.77 ± 5%	0.42	1.75	3.91 ± 13.1% (k=2)
5800	± 50 / ± 100	Body	48.2 ± 5%	6.00 ± 5%	0.42	1.75	3.98 ± 13.1% (k=2)

^c The validity of ± 100 MHz only applies for DASY v4.4 and higher (see Page 2). The uncertainty is the RSS of the ConvF uncertainty at calibration frequency and the uncertainty for the indicated frequency band.

Deviation from Isotropy in HSL

Error (ϕ , θ), $f = 900$ MHz



Uncertainty of Spherical Isotropy Assessment: $\pm 2.6\%$ ($k=2$)



D3: DAE

IMPORTANT NOTICE

USAGE OF THE DAE 3

The DAE unit is a delicate, high precision instrument and requires careful treatment by the user. There are no serviceable parts inside the DAE. Special attention shall be given to the following points:

Battery Exchange: The battery cover of the DAE3 unit is connected to a fragile 3-pin battery connector. Customer is responsible to apply utmost caution not to bend or damage the connector when changing batteries.

Shipping of the DAE: Before shipping the DAE to SPEAG for calibration the customer shall remove the batteries and pack the DAE in an antistatic bag. This antistatic bag shall then be packed into a larger box or container which protects the DAE from impacts transportation. The package shall be marked to indicate that a fragile instrument is inside.

E-Stop Failures: Touch detection may be malfunctioning due to broken magnets in the E-stop. Rough handling of the E-stop may lead to damage of these magnets. Touch and collision errors are often caused by dust and dirt accumulated in the E-stop. To prevent E-stop failure, Customer shall always mount the probe to the DAE carefully and keep the DAE unit in a non-dusty environment if not used for measurements.

Repair: Minor repairs are performed at no extra cost during the annual calibration. However, SPEAG reserves the right to charge for any repair especially if rough unprofessional handling caused the defect.

Important Note:

Warranty and calibration is void if the DAE unit is disassembled partly or fully by the Customer.

Important Note:

Never attempt to grease or oil the E-stop assembly. Cleaning and readjusting of the E-stop assembly is allowed by certified SPEAG personnel only and is part of the annual calibration procedure.

Important Note:

To prevent damage of the DAE probe connector pins, use great care when installing the probe to the DAE. Carefully connect the probe with the connector notch oriented in the mating position. Avoid any rotational movement of the probe body versus the DAE while turning the locking nut of the connector. The same care shall be used when disconnecting the probe from the DAE.



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Client **ADT (Auden)**

Certificate No: **DAE3-510_Jan09**

CALIBRATION CERTIFICATE

Object **DAE3 - SD 000 D03 AA - SN: 510**

Calibration procedure(s) **QA CAL-06.v12
Calibration procedure for the data acquisition electronics (DAE)**

Calibration date: **January 21, 2009**

Condition of the calibrated item **In Tolerance**

This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI).
The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.

All calibrations have been conducted in the closed laboratory facility: environment temperature $(22 \pm 3)^{\circ}\text{C}$ and humidity $< 70\%$.

Calibration Equipment used (M&TE critical for calibration)

Primary Standards	ID #	Cal Date (Certificate No.)	Scheduled Calibration
Fluke Process Calibrator Type 702	SN: 6295803	30-Sep-08 (No: 7673)	Sep-09
Keithley Multimeter Type 2001	SN: 0810278	30-Sep-08 (No: 7670)	Sep-09
Secondary Standards	ID #	Check Date (in house)	Scheduled Check
Calibrator Box V1.1	SE UMS 006 AB 1004	06-Jun-08 (in house check)	In house check: Jun-09

	Name	Function	Signature
Calibrated by:	Eric Hainfeld	Technician	
Approved by:	Fin Bomholt	R&D Director	

Issued: January 21, 2009

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Accreditation No.: **SCS 108**

Glossary

DAE data acquisition electronics
Connector angle information used in DASY system to align probe sensor X to the robot coordinate system.

Methods Applied and Interpretation of Parameters

- *DC Voltage Measurement:* Calibration Factor assessed for use in DASY system by comparison with a calibrated instrument traceable to national standards. The figure given corresponds to the full scale range of the voltmeter in the respective range.
- *Connector angle:* The angle of the connector is assessed measuring the angle mechanically by a tool inserted. Uncertainty is not required.
- The following parameters as documented in the Appendix contain technical information as a result from the performance test and require no uncertainty.
 - *DC Voltage Measurement Linearity:* Verification of the Linearity at +10% and -10% of the nominal calibration voltage. Influence of offset voltage is included in this measurement.
 - *Common mode sensitivity:* Influence of a positive or negative common mode voltage on the differential measurement.
 - *Channel separation:* Influence of a voltage on the neighbor channels not subject to an input voltage.
 - *AD Converter Values with inputs shorted:* Values on the internal AD converter corresponding to zero input voltage
 - *Input Offset Measurement:* Output voltage and statistical results over a large number of zero voltage measurements.
 - *Input Offset Current:* Typical value for information; Maximum channel input offset current, not considering the input resistance.
 - *Input resistance:* DAE input resistance at the connector, during internal auto-zeroing and during measurement.
 - *Low Battery Alarm Voltage:* Typical value for information. Below this voltage, a battery alarm signal is generated.
 - *Power consumption:* Typical value for information. Supply currents in various operating modes.

DC Voltage Measurement

A/D - Converter Resolution nominal

High Range: 1LSB = 6.1 μ V, full range = -100...+300 mV

Low Range: 1LSB = 61nV, full range = -1.....+3mV

DASY measurement parameters: Auto Zero Time: 3 sec; Measuring time: 3 sec

Calibration Factors	X	Y	Z
High Range	404.180 $\pm$ 0.1% (k=2)	404.237 $\pm$ 0.1% (k=2)	404.597 $\pm$ 0.1% (k=2)
Low Range	3.98584 $\pm$ 0.7% (k=2)	3.96418 $\pm$ 0.7% (k=2)	3.97982 $\pm$ 0.7% (k=2)

Connector Angle

Connector Angle to be used in DASY system	42 ° $\pm$ 1 °
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Appendix

1. DC Voltage Linearity

High Range	Input (μV)	Reading (μV)	Error (%)
Channel X + Input	200000	200000.4	0.00
Channel X + Input	20000	20006.50	0.03
Channel X - Input	20000	-20001.19	0.01
Channel Y + Input	200000	200000	0.00
Channel Y + Input	20000	20006.34	0.03
Channel Y - Input	20000	-19999.47	0.00
Channel Z + Input	200000	200000.4	0.00
Channel Z + Input	20000	20005.85	0.03
Channel Z - Input	20000	-20001.94	0.01

Low Range	Input (μV)	Reading (μV)	Error (%)
Channel X + Input	2000	2000.1	0.00
Channel X + Input	200	200.26	0.13
Channel X - Input	200	-200.29	0.14
Channel Y + Input	2000	1999.9	0.00
Channel Y + Input	200	199.55	-0.22
Channel Y - Input	200	-200.78	0.39
Channel Z + Input	2000	2000	0.00
Channel Z + Input	200	199.35	-0.32
Channel Z - Input	200	-200.86	0.43

2. Common mode sensitivity

DASY measurement parameters: Auto Zero Time: 3 sec; Measuring time: 3 sec

	Common mode Input Voltage (mV)	High Range Average Reading (μV)	Low Range Average Reading (μV)
Channel X	200	17.77	16.87
	- 200	-15.55	-16.83
Channel Y	200	16.07	14.66
	- 200	-15.10	-16.55
Channel Z	200	-7.41	-8.67
	- 200	8.31	7.63

3. Channel separation

DASY measurement parameters: Auto Zero Time: 3 sec; Measuring time: 3 sec

	Input Voltage (mV)	Channel X (μV)	Channel Y (μV)	Channel Z (μV)
Channel X	200	-	2.33	0.92
Channel Y	200	0.91	-	2.64
Channel Z	200	-1.49	0.24	-

4. AD-Converter Values with inputs shorted

DASY measurement parameters: Auto Zero Time: 3 sec; Measuring time: 3 sec

	High Range (LSB)	Low Range (LSB)
Channel X	15922	16220
Channel Y	16083	15853
Channel Z	16077	16696

5. Input Offset Measurement

DASY measurement parameters: Auto Zero Time: 3 sec; Measuring time: 3 sec

Input 10M Ω

	Average (μ V)	min. Offset (μ V)	max. Offset (μ V)	Std. Deviation (μ V)
Channel X	0.06	-0.34	0.80	0.21
Channel Y	-1.04	-1.65	0.01	0.25
Channel Z	0.59	-0.07	2.82	0.30

6. Input Offset Current

Nominal Input circuitry offset current on all channels: <25fA

7. Input Resistance

	Zeroing (MOhm)	Measuring (MOhm)
Channel X	0.2001	199.1
Channel Y	0.2001	197.8
Channel Z	0.2001	199.1

8. Low Battery Alarm Voltage (verified during pre test)

Typical values	Alarm Level (VDC)
Supply (+ Vcc)	+7.9
Supply (- Vcc)	-7.6

9. Power Consumption (verified during pre test)

Typical values	Switched off (mA)	Stand by (mA)	Transmitting (mA)
Supply (+ Vcc)	+0.0	+6	+14
Supply (- Vcc)	-0.01	-8	-9